

'Research Insider': «Variability studies in advanced digital semiconductor devices»

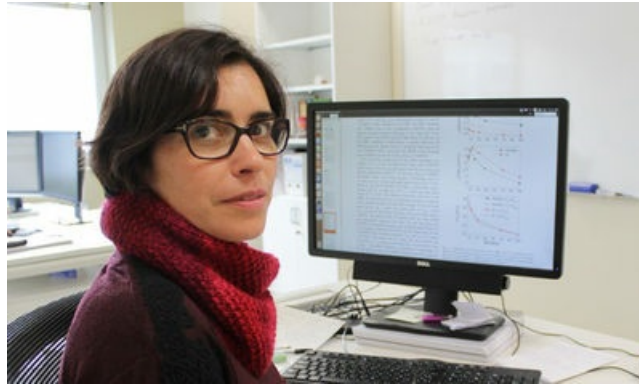
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Lugar: CITIUS Assembly
Hall

Poñente(s): Natalia Seoane Iglesias (Postdoctoral
Researcher)

Idioma: Inglés

Streaming: Non



The progressive scaling of transistors to achieve faster devices and higher circuit density has fuelled the phenomenal success of the semiconductor industry. However, the increasing variability in the device characteristics is among the major challenges to scaling and integration for the present and next generation of devices and circuits.

In this talk, the key aspects of the modelling of advanced digital semiconductor devices will be explored, with special focus on how different sources of variability affect the performance and reliability of these devices.